

## **Technical Note**

# **RELIABILITY QUALITY CONTROL OF LOW NOISE GaAs FET DEVICE**

**NEC Compound Semiconductor Devices, Ltd.**

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## 1. CONCEPT OF RELIABILITY QUALITY CONTROL

NEC Compound Semiconductor Devices, Ltd. has been certified for ISO 9001 and ISO 14001. The company is intent on continually improving its quality system to provide high-quality/environment-friendly products that will satisfy the customer.

The reliability quality control of our microwave semiconductor devices is based on improving the reliability in individual processes, from development design to mass production design, by reflecting customers' needs identified through market research and customer feedback. We also aim to achieve production that maintains a balance between reliability quality and price by adopting effective management methods suitable for the application of individual products, and will devote our full efforts to manufacturing products that will meet our customers' expectations. Toward this realization, shipment and after-sales service are controlled under a coherent system in each process from material procurement to product delivery as follows:

- (1) Selection and procurement of environment-friendly material as well as components/parts
- (2) Quality control and inspection of the product in individual processes up to mass-production
- (3) Confirmation of the quality of the product by reliability testing

In addition, with the expansion and development of the application fields of microwave semiconductor devices such as mobile phones, the number of applications is drastically increasing and the quality expected of our products is steadily growing. In response to these expectations, NEC Compound Semiconductor Devices, Ltd. considers the following items key points:

- (a) improvement of design quality,
- (b) improvement and maintenance of the quality in the production phase, and
- (c) removal of potential defects by setting quality gates in each process.

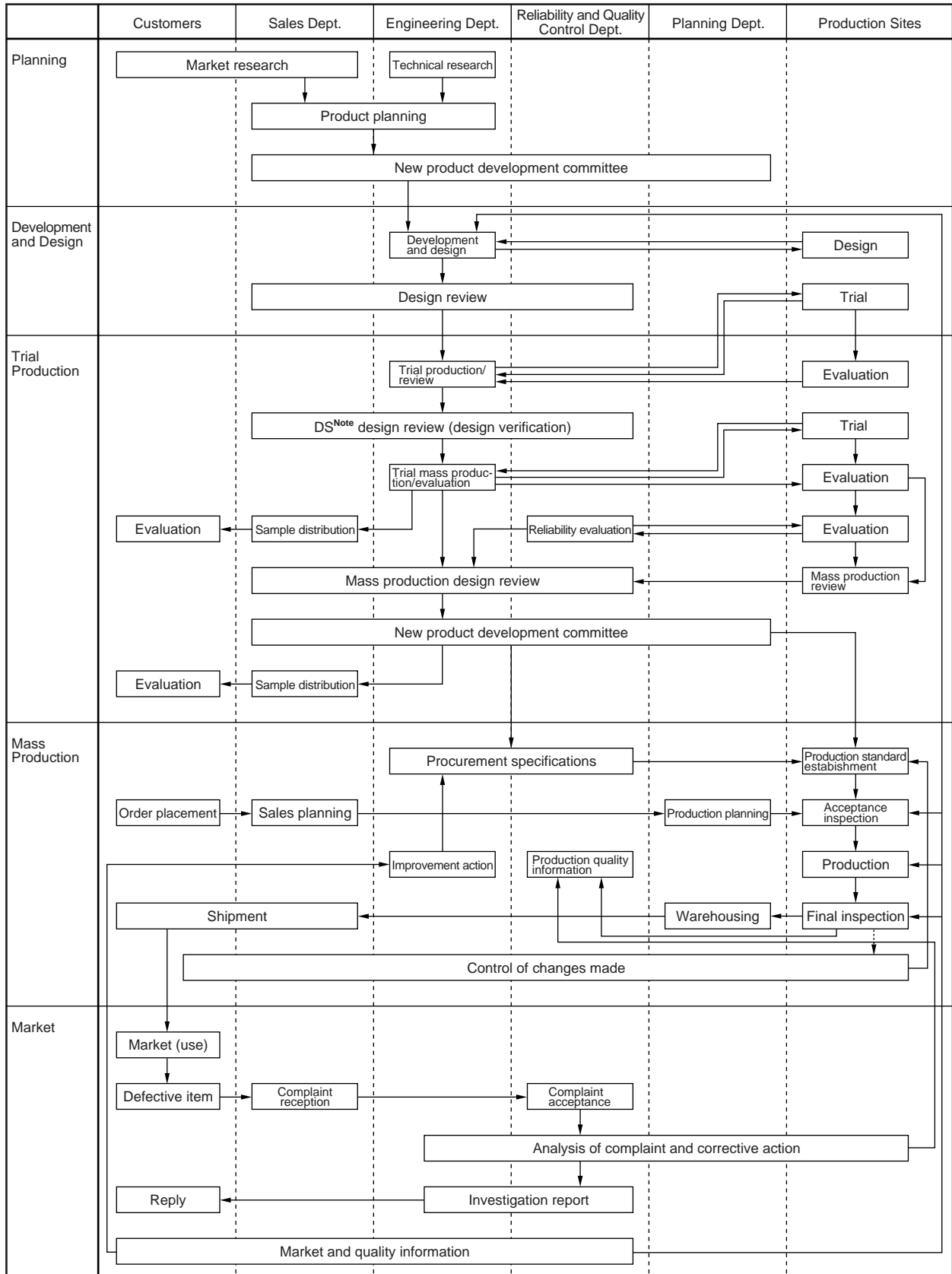
Aspects to be emphasized include

- (i) establishment of reliability by standardization of design rules,
- (ii) identification of non-reliability causes by design review,
- (iii) thorough evaluation of characteristics and reliability testing in development/trial production phase,
- (iv) automation of production facilities and product variation control by facility maintenance,
- (v) enhancement of staff awareness of the quality by small group activities such as QC circle,
- (vi) analysis, feedback and feedforward of quality information including field data, and
- (vii) prevention of defective products by PC (Process Check) in each process and feedback of results to the corresponding process.

By implementing these actions, we commit ourselves to providing semiconductor devices that satisfy the high quality/low price needs of the customer. Moreover, we also pledge to continue our efforts to improve product quality.

The flowchart of the quality (Q) and reliability (R) system is shown in Figure 1-1.

**Figure 1-1 The flowchart of the quality (Q) and reliability (R) system**



**Note** DS : Design Sample

## 2. QUALITY CONTROL OF PRODUCTION PROCESS

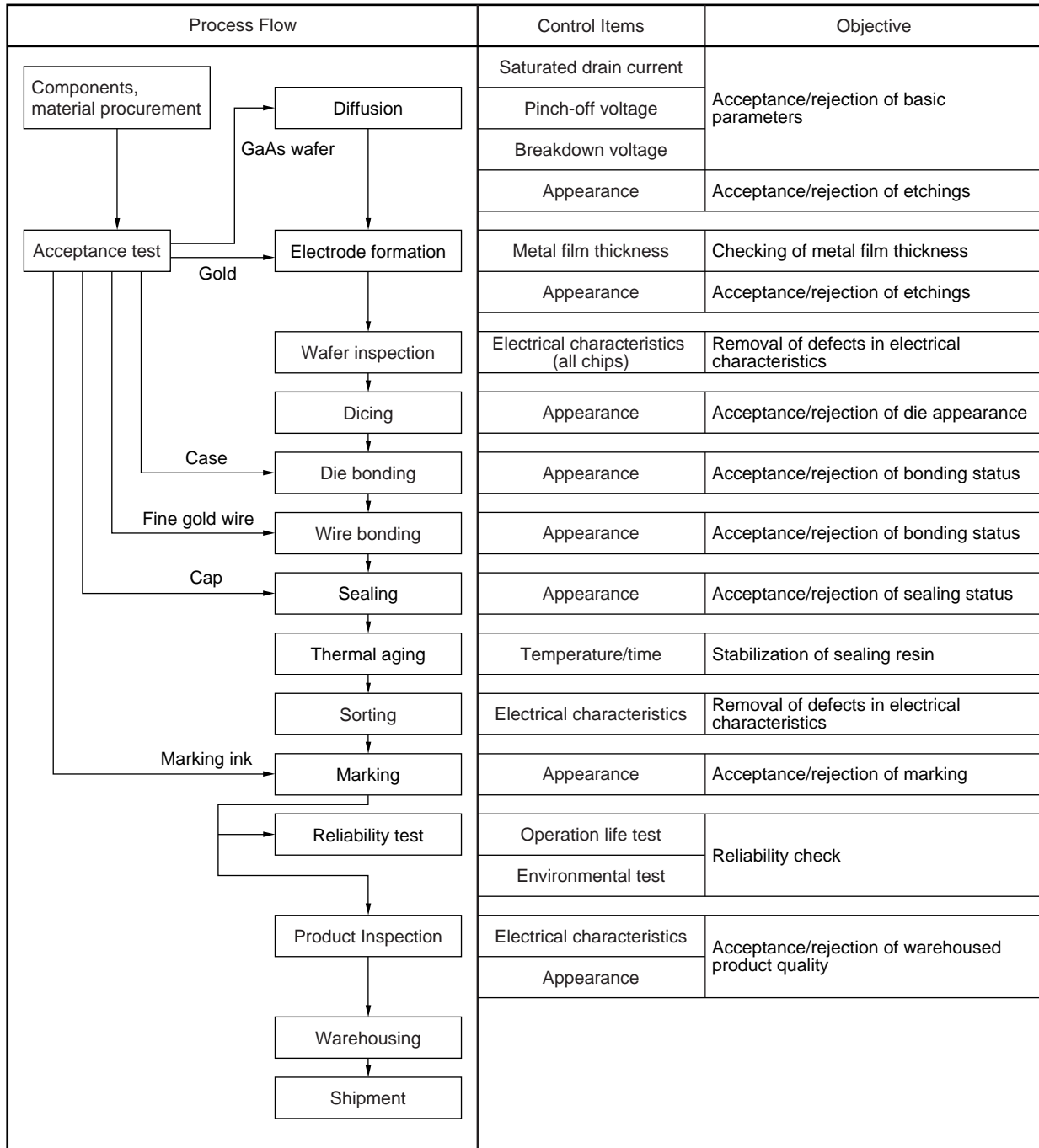
NEC Compound Semiconductor Devices, Ltd. manufactures and releases microwave semiconductor devices focusing on further improvement of the required product reliability by assessing customer requirements as well as the application environment of the product, and incorporating the results into the original design. To realize the reliability quality intended in the design, a production control system is required to obviate any defective elements caused by variations in individual production processes.

Therefore, emphasis is placed on the quality control of parts, components or secondary materials that will determine the reliability quality upon production and on related aspects such as the production environment. Further, by incorporating checking functions in the production processes, half-finished products in each process are checked with optimum frequency against the key control items.

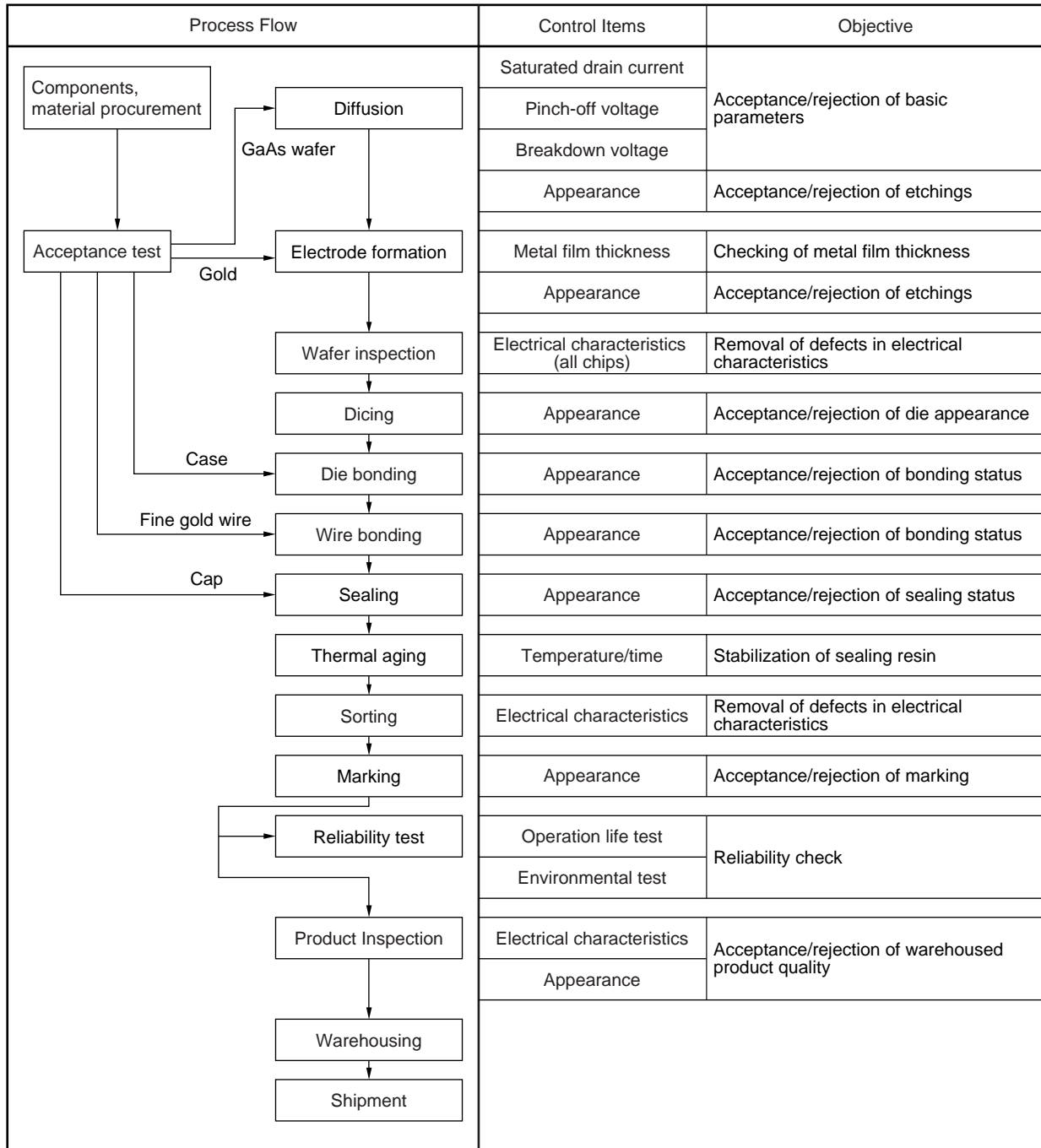
A flowchart example of production process control is shown in Figure 2-1. Components, materials or secondary materials are controlled as described below.

Components, materials and secondary materials such as chemicals or high-purity gas are procured through the specified vendors. Acceptance testing is performed largely by sampling based on JIS Z 9015 or other procurement standards used by NEC Compound Semiconductor Devices, Ltd. The result of the acceptance test is monitored, and if necessary, corrective action is taken or factory inspections are conducted at the specified vendors to stabilize the quality of the purchased products.

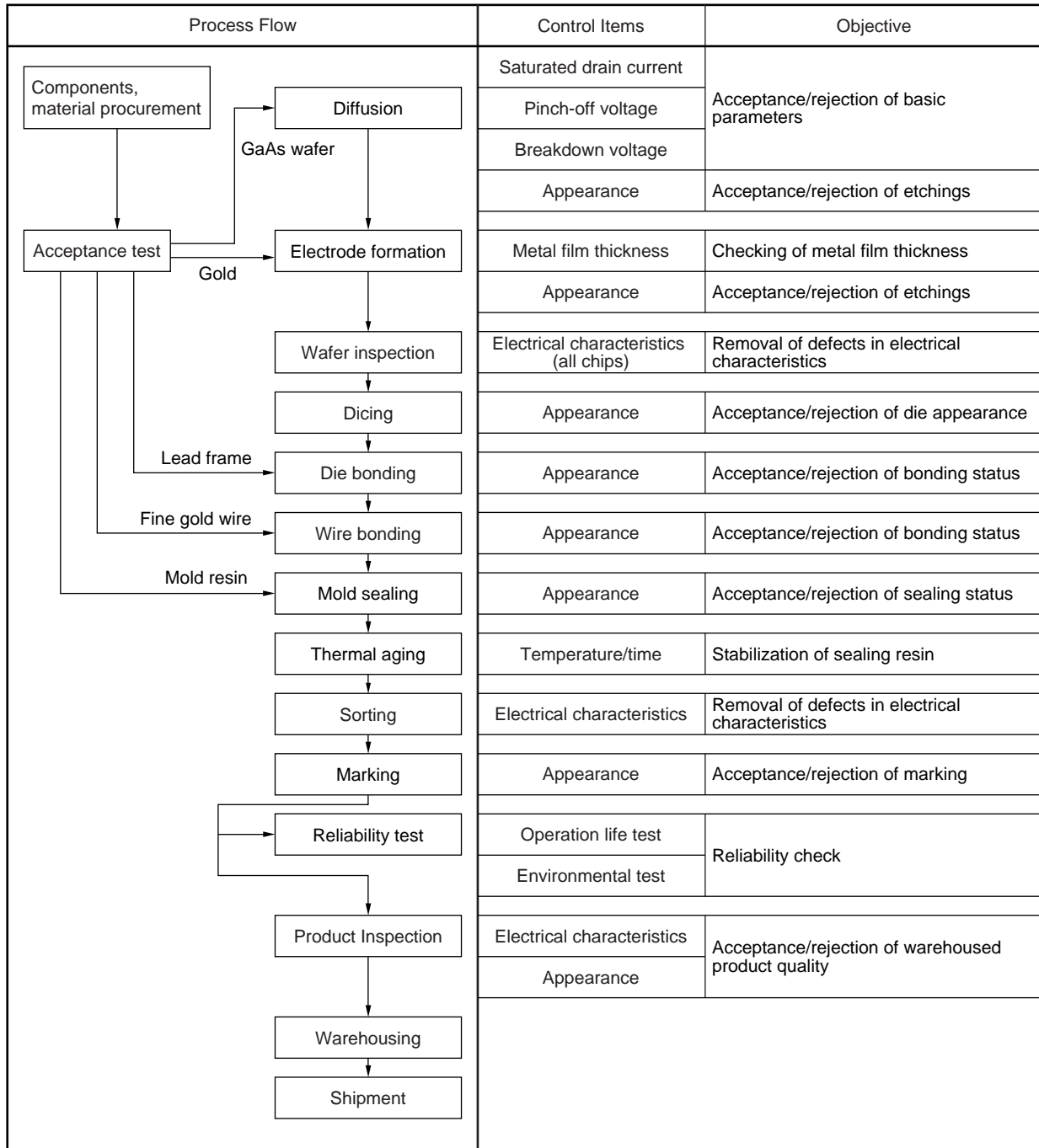
**Figure 2-1 An example of production process control flowchart of Low noise GaAs FET ( $\mu$ -X package)**



**Figure 2-2 An example of production process control flowchart of Low noise GaAs FET (hollow plastic package)**



**Figure 2-3 An example of production process control flowchart of Low noise GaAs FET (plastic package)**



### 3. PRODUCTION INSPECTION

Product inspections are conducted by sampling to determine whether or not the package appearance and electrical characteristics of products that have already passed the sorting inspection meet the specified standard.

An example of this inspection is shown below.

(1) Low noise GaAs FET ( $\mu$ -X package)

Item	Parameter	Sampling Inspection		
		LTPD	Number of Samples	Number Passed Inspection
Open/Short	Open, Short	10%	22	0
Breakdown Voltage, Leak Current	$I_{GSO}$ , $BV_{GSO}$ , $V_{GF}$ , $I_{GDO}$ , $BV_{GDO}$	10%	22	0
Transconductance, Saturated Drain Current	$g_m$ , $I_{DSS}$	10%	22	0
Pinch-off Voltage	$V_p$	10%	22	0
RF Characteristics	NF, $G_a$	5%	45	0
Critical Package Appearance	Case cracking, Lead deformation, Bent leads, No lead plating, Missing markings	1%	231	0
Moderate Package Appearance	Case chipping, Defective lead plating, Illegible markings	1%	231	0

(2) Low noise GaAs FET (hollow plastic package, plastic package)

Item	Parameter	Sampling Inspection		
		LTPD	Number of Samples	Number Passed Inspection
Open/Short	Open, Short	10%	22	0
Breakdown Voltage, Leak Current	$I_{GSO}$ , $BV_{GSO}$ , $V_{GF}$ , $I_{GDO}$ , $BV_{GDO}$	10%	22	0
Transconductance, Saturated Drain Current	$g_m$ , $I_{DSS}$	10%	22	0
Pinch-off Voltage	$V_p$	10%	22	0
RF Characteristics	NF, $G_a$	5%	45	0
Critical Package Appearance	Resin cracking, Lead deformation, Bent leads, No lead plating, Missing markings	1%	231	0
Moderate Package Appearance	Defective resin molding/Chipping, Defective lead plating, Illegible markings	1%	231	0

## 4. RELIABILITY TEST

Reliability tests are conducted regularly based upon EIAJ ED-4701, MIL-STD-750 and other standards. Examples of the tests and of the failure criteria are shown in 4. 1 and 4. 2 below.

### 4. 1 Test Contents

(1) An example of Low noise GaAs FET ( $\mu$ -X package, hollow plastic package) is shown below.

Test Item	Test Conditions	Number of Samples	Related Standards
			EIAJ ED-4701
Solderability	215 $\pm$ 5°C or 245 $\pm$ 5°C, 5 seconds	11	303
Soldering Heat	260 $\pm$ 5°C, 10 seconds	11	301
Temperature Cycle	T <sub>stg min.</sub> <sup>Note 1</sup> to T <sub>stg max.</sub> <sup>Note 1</sup> 30 minutes each, 100 cycles	11	105
Power Burn-in	T <sub>ch</sub> = T <sub>ch max.</sub> , V <sub>DS</sub> = V <sub>DS max.</sub> <sup>Note 2</sup> , I <sub>DS</sub> = I <sub>DS max.</sub> <sup>Note 2</sup>	20	101
High-temperature Reverse Bias	T <sub>A</sub> = 150°C, V <sub>GSS</sub> = V <sub>GS max.</sub> <sup>Note 1</sup> $\times$ 0.8	20	–
High-temperature High-humidity Reverse Bias	T <sub>A</sub> = 85°C, Rh = 85%, V <sub>GSS</sub> = V <sub>GS max.</sub> <sup>Note 1</sup> $\times$ 0.8, 1 000 hours	20	102
Autoclave (Pressure Cooker)	T <sub>A</sub> = 125°C, P = 230 kPa, 48 hours	20	–
High-temperature Storage	T <sub>stg max.</sub> <sup>Note 1</sup> , 1 000 hours	20	201
Low-temperature Storage	T <sub>stg min.</sub> <sup>Note 1</sup> , 1 000 hours	20	202
Terminal Strength (pulling)	Apply the specified weight, Keep for 10 seconds	11	401
Terminal Strength (bending)	Apply the specified weight, 90°, Once	11	401
Electrostatic Discharge Sensitivity	C = 200 pF, R = 0 $\Omega$ , Once, Between the weakest terminals	20	305

**Notes 1.** Absolute maximum ratings

**2.** Recommended operating conditions

(2) An example of Low noise GaAs FET (plastic package) is shown below.

Test Item	Test Conditions	Number of Samples	Related Standards
			EIAJ ED-4701
Solderability	215±5°C or 245±5°C, 5 seconds	11	303
Soldering Heat	260±5°C, 10 seconds	11	301
Temperature Cycle	T <sub>stg</sub> min. <sup>Note 1</sup> to T <sub>stg</sub> max. <sup>Note 1</sup> 30 minutes each, 100 cycles	11	105
Power Burn-in	T <sub>ch</sub> = T <sub>ch</sub> max., V <sub>DS</sub> = V <sub>DS</sub> max. <sup>Note 2</sup> , I <sub>DS</sub> = I <sub>DS</sub> max. <sup>Note 2</sup>	20	101
High-temperature Reverse Bias	T <sub>A</sub> = 150°C, V <sub>GSS</sub> = V <sub>GS</sub> max. <sup>Note 1</sup> × 0.8	20	–
High-temperature High-humidity Reverse Bias	T <sub>A</sub> = 85°C, Rh = 85%, V <sub>GSS</sub> = V <sub>GS</sub> max. <sup>Note 1</sup> × 0.8, 1 000 hours	20	102
Autoclave (Pressure Cooker)	T <sub>A</sub> = 125°C, P = 230 kPa, 96 hours	20	–
High-temperature Storage	T <sub>stg</sub> max. <sup>Note 1</sup> , 1 000 hours	20	201
Low-temperature Storage	T <sub>stg</sub> min. <sup>Note 1</sup> , 1 000 hours	20	202
Terminal Strength (pulling)	Apply the specified weight, Keep for 10 seconds	11	401
Terminal Strength (bending)	Apply the specified weight, 90°, Once	11	401
Electrostatic Discharge Sensitivity	C = 200 pF, R = 0 Ω, Once, Between the weakest terminals	20	305

- Notes**
1. Absolute maximum ratings
  2. Recommended operating conditions

#### 4.2 Failure Criteria

An example of Low noise GaAs FET ( $\mu$ -X package, hollow plastic package, plastic package) is shown below.

Test Item	Failure Criteria		
	Parameter	Lower	Upper
Soldering Heat, Temperature Cycle, Power Burn-in, High-temperature Reverse Bias, High-temperature High-humidity Storage, PCT, High-temperature Storage, Low-temperature Storage, Electrostatic Discharge Sensitivity	Gate to source leak current (I <sub>gso</sub> )	–	S × 2 or S + 300 nA <sup>Note</sup>
	Saturated drain current (I <sub>DSS</sub> )	S × 0.8	S × 1.2
	Pinch-off voltage (V <sub>p</sub> )	S × 0.8	S × 1.2
	Transconductance (g <sub>m</sub> )	S × 0.8	S × 1.2
Terminal Strength	Lead appearance	No evidence of breakage or loosening	
Solderability		Solder covers 95% or more of the surface	

**Note** The greater of S × 2 or S + 300 nA should be applied.

**Remark** S : Initial value

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